



COST Action IC 1407

“Advanced Characterisation and Classification of Radiated Emissions in Densely Integrated Technologies (ACCREDIT)”

WG-4: Guidelines for the formulation of standards

V. Mariani Primiani

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COST Association
Avenue Louise 149 | 1050 Brussels, Belgium
t: +32 (0)2 533 3800 | f: +32 (0)2 533 3890
office@cost.eu | www.cost.eu

WG-4 participants

- Dave Thomas
- Peter Russer
- Andy Marvin
- Davy Pissoort
- Ferran Silva
- John Dawson
- Gabriele Gradoni
- M. Cabello
- Dias Angulo
- Johannes Russer
- Marco Azpúrua
- Valter Mariani Primiani
- Zbigniew Jóskiewicz
- Jean-Baptiste Gros
- Sasko Ristov
- Franco Moglie
- Luca Bastianelli
- Eugen Coca

WG-4 description

Cost benefit analysis and a complete set of guidelines will be provided giving the **spatial and temporal sampling** needed to fully characterise the noisy fields from mixed signal devices **such that their performance in any environment can be fully predicted**. This should form the basis **for the construction of new emission measurement standards** that will be of significant value to the industrial community. Care will be taken to make these techniques accessible to end users.



POTENTIALLY INTERESTING STANDARDS

“Emission standards”

- EN xxx based on CISPR (example CISPR 16)
- IEEE Standards ?
-

“Immunity” ?

Are only basic standards involved or should we move also in generic and/or product standards considering the particular EUTs of our COST action ?



EMISSION STANDARDS

Receiver Spec.

Test site spec.

Measurement
procedures

Result evaluation
methods

Limits



RECEIVER

- Time domain measurements
 - Comply to CISPR 16 specifications
 - Many papers (Russer et al.) showed the equivalence with FD measurements and that they are faster

- Detectors (are actual Pk, Avg, RMS adequate ?)

- RBWs (are actual CISPR BWs adequate ?)

- Should we propose specific requirements for non-stationary emissions/stochastic signals ?

MEASUREMENT PROCEDURES

- Dwell time
- Inspection angles
 - TD techniques allow to speed up also angular characterization of the EUT (Russer et al. TEMC 2008)
- Spatial sampling
- Polarizations

- Should we propose specific requirements for non-stationary emissions/stochastic signals ?
- How to manage possible stochastic radiation patterns ?
(Gradoni et al. New Journal of Physics 2015, Thomas et. al, IEEE 2015))

Results analysis - Limits

- Should a specific statistical analysis be introduced in case of stochastic sources ?
 - F. Silva et al. (2015) have faced the problem of statistical analysis of pk detector output data

- Should the limits be changed for stochastic sources ?
(strictly related to detector choice)

New standards for measurements ?

- Should we propose a specific standard for NF TD measurements ?
 - Sampling rate
 - Spatial sampling
 - Record length
 - Probe calibration
 - Sensitivity
 - Resolution
 -
 - **NF-TD set-up as a new test site**

- Could it be proposed as an alternative (but correlated) technique for EMC control ? (see the IEC 61967-6 for IC emissions, IEC 62132-9 for IC CW immunity, and IEC 62215-6 for IC transient immunity)

New standards for modelling ?

- ❑ Would we like to propose a standard for NF equivalent source modelling ?
(see for example IEC 62433-x for IC EMC modelling, proposal)
 - Correlation functions
 - Equivalent dipoles
 - Spherical waves
 - ...

ACTIONS

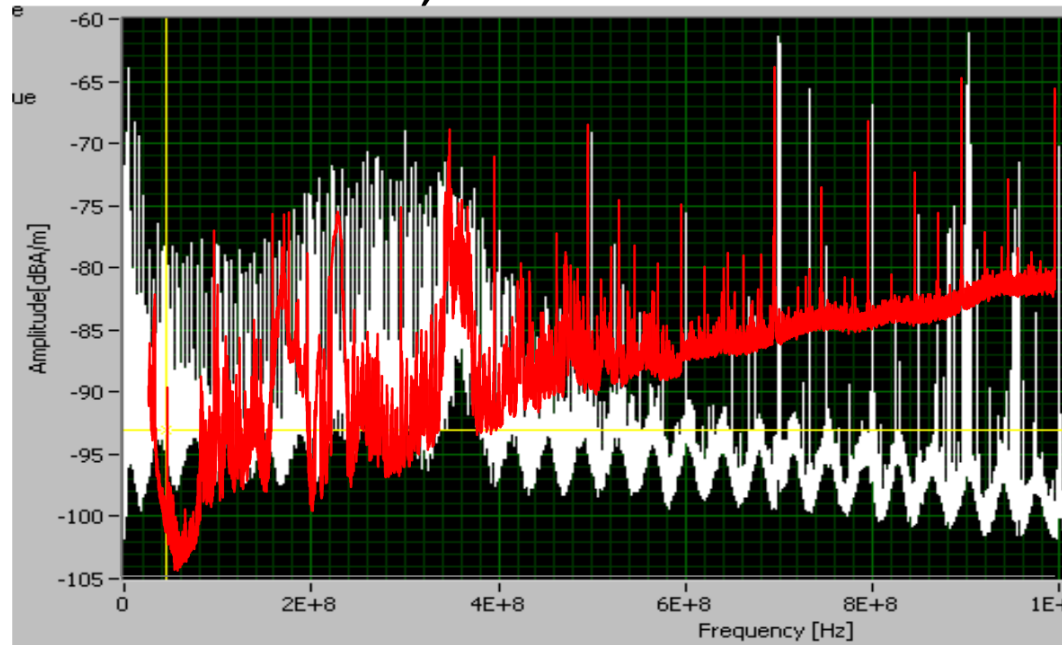
- Measurement data for comparison
 - Is the collection of emission data from real PCBs feasible ?
 - Round Robin measurements to highlight possible deficiencies in current standards
 - Is there anybody who has already done specific comparisons ?
Could available data be shared ?

- Simulation campaign to support the comparison
 - Is the simulation of a FF test useful to discover deficiencies in evaluating emissions from stochastic sources ?
 - Other ?

- Is there anybody already involved in standardization Committees who can propose a specific seminar ?

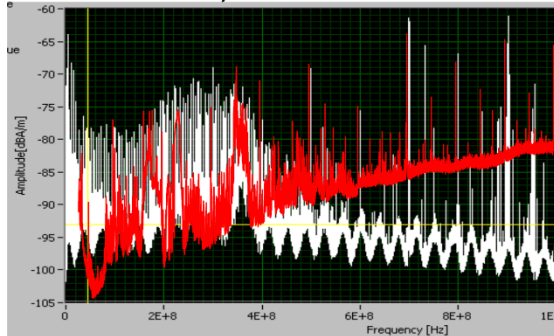
EXAMPLE

White: Nf scan, Red: Semi anechoic



From WS11: “Challenges in near field scanning real world electronic Modules” by Anders P. Mynster, DELTA – Danish electronics, lights and acoustics. EMC Europe – 2015 – DRESDEN.

White: Nf scan, Red: Semi anechoic



Why below 300 MHz many components are missed by SAC measurements ?

- Was it a problem of the SAC ?
- Was it a spatial or time sampling problem ?
- Was it a problem due to the reactive near field that vanishes in FF ?
 - If so, should it be considered a drawback of the NF techniques ?
 - Or is it a huge advantage aiming at the formulation of NF limits (Xtalk control and limitation in complex PCB assemblies) ?



IC 1407 ACCREDIT
WG-4. Standards

DISCUSSION IS OPEN



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